



Electrical Characteristic Summary:

QC ambient correlation data between the source tester (Micro Flex) and the target tester (T2000) is provided separate qualification report together with the Final PCN "SBCC_uflex to T2000_Device_Test_Qualification_Report"

The same correlation procedure is used, as in previous PCN's covering the release of additional tester platforms

- 2 correlation units are serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test is done at room temperature, using the QC program.
 - Then, the same correlation unit is used to gather data on target tester T2000.
 - The same datalogging procedure used for Micro Flex is followed for T2000.

Full parametric correlation are performed and for every test the shift is evaluated as follows:

$$\Delta\text{mean} = \text{abs}(\text{mean}(\text{ref}) - \text{mean}(\text{qual}))$$

$$\Delta\text{sigma} = 0$$

$$\Delta\text{sigma} = \text{sigma}(\text{qual}) - \text{sigma}(\text{ref})$$

$$\text{if } \text{sigma}(\text{qual}) < \text{sigma}(\text{ref})$$

$$\text{if } \text{sigma}(\text{qual}) > \text{sigma}(\text{ref})$$

$$\text{shift} = \Delta\text{mean} + 4 * \Delta\text{sigma}$$

**If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test,
else correlation is NOK for this test**

- 10 Rejects from Hot and 10 rejects from Cold are serialized and datalogged on Micro Flex. The same devices are tested on T2000. Results should match, deviations must be explained.

List of Affected Customer Specific Parts:

NOTE: Please be informed that parts impacted by this PDN/PCN are Special/Customer specific parts, thus MPN & CPN info will be available to affected customers only by clicking the "Custom PCN for Selected Company Button" in the Document Analysis page of PCMS/PCN Alert.